

Notice of References Cited	Application/Control No. 10/783,830	Applicant(s)/Patent Under Reexamination KRUTKO ET AL.	
	Examiner Andy Huynh	Art Unit 2818	Page 1 of 1

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	B	US-5,243,207	09-1993	Plumton et al.	257/192
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NON-PATENT DOCUMENTS

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